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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Maki TANAKA et al.  
Serial No.: 09/942,213  
Filed: August 30, 2001  
For: **METHOD AND APPARATUS FOR INSPECTING A  
SEMICONDUCTOR DEVICE**  
Group: 2625  
Examiner: John B. Strege

AMENDMENT

**Mail Stop Amendment**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**November 18, 2004**

Sir:

In response to the Office Action (Paper No. 8) dated on August 23, 2004,  
please amend the above-identified application as follows.

**Amendments to the Claims** begin on page 2 of this paper.

**Remarks/Arguments** begin on page 8 of this paper.